

Bill Bulat Febuary 2000



- ◆ Thermal Strain Calculation May be Performed Using 2 Different Kinds of Thermal Coefficient of Expansion (CTE)
 - Instantaneous CTE
 - » Vendor-Supplied Data Often in this Form

$$\approx \varepsilon(T) = \alpha ins(T) dT$$

Secant or Average CTE

» <u>Used by ANSYS</u>

$$\approx \varepsilon(T) = \alpha_0(T)^*(T - TREF)$$

◆ TREF = Temperature at Which Thermal Strain is Zero

CSI ANSYS Tip of the Week



- ◆ In ANSYS, TREF May Be Assigned in 2 Different Ways:
 - 1 "Globally" TREF is Same for All Parts of Model
 - » Cannot Change Between Load Steps
 - » [TREF, reference temperature] (Default: 0)
 - 2 As a Material Property:
 - » Different Materials May Have Different Values
 - » [MP, #, REFT, reference temperature]
 - » Values Specified as Material Properties Take Precedence Over Global Setting, All Others Default to Global Setting

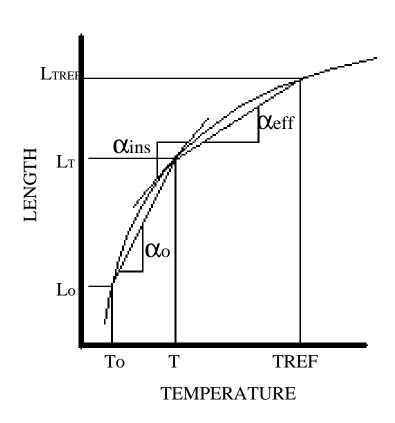
CSI ANSYS Tip of the Week



- ◆ Clearly, if Vendor-Supplied Data is in Instantaneous Form, it Must be Converted to Secant Form Before Using in ANSYS Analysis
- ◆ Even if Vendor-Supplied Data is Already in Secant form, the Values Probably Still Require Conversion to Those of <u>Effective</u> <u>Thermal</u> <u>Coefficient</u> of <u>Expansion</u>



Differences Between Instantaneous (α_{ins}), Secant (α_o), and Effective (α_{eff}) CTE



- ◆ A Test is Performed with a Specimen Starting at Length Lo at Temperature To
- LT = Length @ Temperature T
- ◆ LTREF = Length @ TREF
- If Lo = 1.0, then:
- αo = Secant CTE at
 Temperature T from Test
- αins = Instantaneous CTE at Temperature T from Test
- αeff = Effective CTE Based on Stress-Free Temp (TREF) at Temperature T (Use in ANSYS Analyses)

CSI ANSYS Tip of the Week

- Note that α eff ≠ α o



- ◆ Vendor-Supplied Values Must be Modified if:
 - Data is Secant (or Average) and Data is Temperature
 Dependent and Reference Temperature NOT EQUAL
 to Component Strain Free Temperature, or if
 - Data is "Instantaneous"



- ◆ Modifying Secant (Average) Values Based on a Temperature (To) Other Than the Desired Stress-Free Temperature (TREF)
 - Use [MPAMOD, MAT, DEFTEMP]
 - » *MAT*: Identification Number Material to be Modified
 - » DEFTEMP: "Defining" Temperature (To)
 Corresponding to Test Specimen Length Lo
 (Temperature at Which Thermal Strain from Test
 Data is Zero)
 - » Must Define TREF Prior to Using Command:
 - ◆ [MP,#,REFT,stress-free temperature]

CSI ANSYS Tip of the Week



- ◆ Converting Instantaneous Data to Secant Data
 - Requires Evaluation of Integral

$$\approx \varepsilon(T) = \alpha ins(T) dT$$

 No Convenient Command Exists in ANSYS, but One Can Perform Operations Between Single Column Array Parameters with [*VOPER] Command